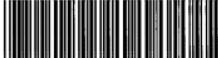


<b>Search Notes</b> 				Application/Control No.	Applicant(s)/Patent under Reexamination	
				10/816,622	OOTSU ET AL.	
				Examiner	Art Unit	
				Binh X. Tran	1765	
<b>SEARCHED</b>				<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>		
Class	Subclass	Date	Examiner		DATE	EXMR
216	7	6/7/2006	BT	Update search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	6/7/2006	BT
216	11	6/7/2006	BT			
216	24	6/7/2006	BT			
216	96	6/7/2006	BT			
<b>INTERFERENCE SEARCHED</b>						
Class	Subclass	Date	Examiner			
216	7	6/7/2006	BT			
216	11	6/7/2006	BT			
216	24	6/7/2006	BT			
216/96		6/7/2006	BT			